**ON Semiconductor**<sup>®</sup>



NCV8730BMTWADJTBGEVB (DFN-6) Evaluation Board – Test procedure





### Output voltage accuracy test:

- 1) Apply no load.
- 2) Apply input voltage  $V_{\text{IN}}$  =  $V_{\text{OUT-NOM}}$  + 1V and  $V_{\text{IN}}$  >= 2.7V.
- 3) Measure output voltage V<sub>OUT-SNS</sub>.

### Notes:

• V<sub>IN</sub> and I<sub>LOAD</sub> could be changed in ranges specified in datasheet to measure line and load regulations.

### Quiescent current test:

### 1) Apply no load.

- 2) Apply input voltage  $V_{IN} = V_{OUT-NOM} + 1V$  and  $V_{IN} >= 2.7V$ .
- 3) Measure input current  $I_{IN}$  (note that  $I_Q$  is  $I_{IN}$  at no load).

### Notes:

- V<sub>IN</sub> could be changed in range specified in datasheet.
- $I_{LOAD}$  must be zero at this test to measure  $I_Q$ .
- At ADJ device version the current through R<sub>1</sub>/R<sub>2</sub> resistor divider is added to quiescent current of the LDO. The value of I<sub>R1R2</sub> could be computed as I<sub>R1R2</sub> = V<sub>OUT</sub> / (R<sub>1</sub> + R<sub>2</sub>) and then could be subtracted from measured input current I<sub>IN</sub> to obtain LDO's quiescent current I<sub>Q</sub> = I<sub>IN</sub> I<sub>R1R2</sub>.

# Dropout voltage test:

- 1) Apply desired load current (for example 150mA).
- 2) Apply input voltage  $V_{IN} = V_{OUT-NOM} + 1V$  and  $V_{IN} >= 2.7V$ .
- 3) Decrease input voltage (V<sub>IN</sub>) until measured output voltage (V<sub>OUT-SNS</sub>) falls out of regulation to level V<sub>OUT-SNS</sub> = V<sub>OUT-NOM</sub> 100mV.
- 4) Compute dropout voltage  $V_{DO} = V_{IN-SNS} V_{OUT-SNS}$ .

# Notes:

During this testing the LDO is heated up by dissipated power P<sub>DIS</sub> = (V<sub>IN</sub> − V<sub>OUT</sub>) \* I<sub>OUT</sub> so take in mind that measured dropout voltage could be higher than a typical value specified at T<sub>J</sub> = 25degC.